

Search Notes



Application/Control No.

10/656,353

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

HEGER ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	5	5/24/2005	K-CC
	10		
	706		
	710		
438	714		
216	59		
216	61	5/24/05	K-CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST key words search, USPAT, US-PGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search.	5/24/2005	K-CC